

# Silicon Carbide (SiC) Cascode JFET Module -

# EliteSiC, Full-Bridge Module, 1200 V, 70 mohm

# UFB15C12E1BC3N

## Description

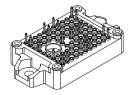
This SiC FET device is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's silicon-like gate-drive characteristics allows the use of unipolar gate drives, compatible with Si IGBTs, Si FETs, SiC MOSFETs or Si super-junction devices. Available in the PIM20 module package, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads, and any application requiring standard gate drive. Advanced Ag sintering die attach technology gives the module superior thermal performance.

#### **Features**

- On-resistance  $R_{DS(on)}$ : 70 m $\Omega$  (Typ)
- Operating Temperature: 150 °C (Max)
- Excellent Reverse Recovery: Q<sub>rr</sub> = 140 nC
- Low Body Diode V<sub>FSD</sub>: 1.4 V
- Low Gate Charge:  $Q_G = 46 \text{ nC}$
- Threshold Voltage V<sub>G(th)</sub>: 5 V (Typ) Allowing 0 to 15 V Drive
- ESD Protected, HBM Class 2 and CDM Class 3
- This Device is Pb-Free, Halogen Free and is RoHS Compliant

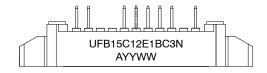
#### **Typical Applications**

- Ev Charging
- PV Inverters
- Switch Mode Power Supplies
- Power Factor Correction Modules
- Motor Drives
- Induction Heating



PIM20 CASE 180DG

#### MARKING DIAGRAM

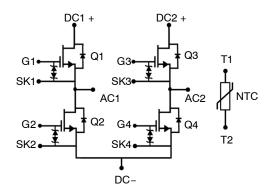


UFB15C12E1BC3N = Specific Device Code

= Assembly Location

YY = Year WW = Work Week

#### **PIN CONNECTIONS**



#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 10 of this data sheet.

#### **MAXIMUM RATINGS**

Parameter	Symbol	Test Conditions	Value	Unit
Drain-source Voltage	V <sub>DS</sub>		1200	V
Gate-source Voltage	V <sub>GS</sub>	DC	-20 to +20	V
		AC (f > 1 Hz)	-25 to +25	1
Continuous Drain Current (Note 1)	I <sub>D</sub>	T <sub>C</sub> = 25 °C	24	Α
		T <sub>C</sub> = 105 °C	15	Α
Pulsed Drain Current (Note 2)	I <sub>DM</sub>	T <sub>C</sub> = 25 °C	80	Α
Power Dissipation	P <sub>tot</sub>	T <sub>C</sub> = 25 °C	96	W
Maximum Junction Temperature	T <sub>J, max</sub>		150	°C
Operating and Storage Temperature	T <sub>J</sub> , T <sub>STG</sub>		-55 to 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL CHARACTERISTICS

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$		-	1.0	1.3	°C/W

#### **NTC THERMAL CHARACTERISTICS**

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Rated Resistance	R <sub>25</sub>	T <sub>NTC</sub> = 25 °C	_	5	_	kΩ
Resistance Value Tolerance	ΔR/R		-5	_	5	%
Power Dissipation	P <sub>25</sub>		_	_	20	mW
B Constant	B <sub>25/50</sub>	$R_2 = R_{25} \exp [B_{25/50} (1/T2 - 1/(298.15 K))]$	-	3375	-	k

#### **MODULE**

Parameter	Symbol	Test Conditions	Value		Unit	
Isolation Voltage	V <sub>ISOL</sub>		-	3	_	kV
Internal Isolation			-	Al <sub>2</sub> O <sub>3</sub>	_	
Creepage Distance		Terminal to Heatsink	_	12.7	_	mm
		Terminal to Terminal	-	6.3	_	
Clearance Distance		Terminal to Heatsink	-	10	-	
		Terminal to Terminal	-	5	-	
Stray Inductance Module	L <sub>sCE</sub>		-	11		nΗ

Limited by T<sub>J, max</sub>.
 Pulse width t<sub>p</sub> limited by T<sub>J, max</sub>.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = +25 °C unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
TYPICAL PERFORMANCE - STATIC	•					
Drain-source Breakdown Voltage	BV <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	1200	_	-	V
Total Drain Leakage Current	I <sub>DSS</sub>	$V_{DS}$ = 1200 V, $V_{GS}$ = 0 V, $T_{J}$ = 25 °C	-	0.5	75	μΑ
		V <sub>DS</sub> = 1200 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	2.5	-	
Total Gate Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, T_J = 25 \text{ °C}, \ V_{GS} = -20 \text{ V} / +20 \text{ V}$	-	6	20	μΑ
Drain-source On-resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 12 V, I <sub>D</sub> = 15 A, T <sub>J</sub> = 25 °C	-	70	90	mΩ
		V <sub>GS</sub> = 12 V, I <sub>D</sub> = 15 A, T <sub>J</sub> = 125 °C	_	111	-	1
		V <sub>GS</sub> = 12 V, I <sub>D</sub> = 15 A, T <sub>J</sub> = 150 °C	_	129	-	1
Gate Threshold Voltage	V <sub>G(th)</sub>	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 10 mA	4	5	6	V
Gate Resistance	R <sub>G</sub>	f = 1 MHz, open drain	-	4.5	-	Ω
TYPICAL PERFORMANCE - REVERSE DIO	DE					•
Diode Continuous Forward Current (Note 3)	I <sub>S</sub>	T <sub>C</sub> = 25 °C	_	_	24	Α
Diode Pulse Current (Note 4)	I <sub>S, pulse</sub>	T <sub>C</sub> = 25 °C	_	_	80	Α
Forward Voltage	V <sub>FSD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 15 A, T <sub>J</sub> = 25 °C	_	1.4	2	V
		V <sub>GS</sub> = 0 V, I <sub>S</sub> = 15 A, T <sub>J</sub> = 150 °C	_	1.63	-	
Reverse Recovery Charge	Q <sub>rr</sub>	V <sub>DS</sub> = 800 V, I <sub>S</sub> = 15 A,	_	140	-	nC
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0 \text{ V, } R_G = 5 \Omega,$ $di/dt = 1200 \text{ A/}\mu\text{s, } T_J = 25 \text{ °C}$	-	35	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	V <sub>DS</sub> = 800 V, I <sub>S</sub> = 15 A,	-	141	-	nC
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS}$ = 0 V, R <sub>G</sub> = 5 Ω, di/dt = 1200 A/μs, T <sub>J</sub> = 150 °C	_	35	-	ns
TYPICAL PERFORMANCE - DYNAMIC	1	, ,	I			
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V,	-	1445	-	pF
Output Capacitance	C <sub>oss</sub>	f = 100 kHz	_	55	_	
Reverse Transfer Capacitance	C <sub>rss</sub>		_	2	_	
Effective Output Capacitance, Energy Related	C <sub>oss(er)</sub>	V <sub>DS</sub> = 0 V to 800 V, V <sub>GS</sub> = 0 V	-	63	-	pF
Effective Output Capacitance, Time Related	C <sub>oss(tr)</sub>		_	128	-	1
C <sub>OSS</sub> Stored Energy	E <sub>oss</sub>	V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V	_	20	-	μJ
Total Gate Charge	$Q_{G}$	$V_{DS} = 800 \text{ V}, I_D = 15 \text{ A},$	_	46	-	nC
Gate-drain Charge	$Q_{GD}$	$V_{GS} = -5 \text{ V to } 15 \text{ V}$	_	7	-	
Gate-source Charge	Q <sub>GS</sub>		_	19	_	
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> = 800 V, I <sub>D</sub> = 15 A,	_	22.4	-	ns
Rise Time	t <sub>r</sub>	Gate Driver = $-5$ V to +15 V, R <sub>G ON</sub> = 1 $\Omega$ ,	_	18.4	-	1
Turn-off Delay Time	t <sub>d(off)</sub>	$R_{G OFF} = 20 \Omega$ , Inductive Load,	_	65	-	1
Fall Time	t <sub>f</sub>	FWD: Same Device with	_	10.4	-	1
Turn-on Energy	E <sub>ON</sub>	$V_{GS}$ = 0 V and $R_G$ = 20 $\Omega$ , $T_J$ = 25 °C (Notes 5, 7)	_	396	-	μJ
Turn-off Energy	E <sub>OFF</sub>	, ,	_	42	-	1
Total Switching Energy	E <sub>TOTAL</sub>	1	_	438	_	1

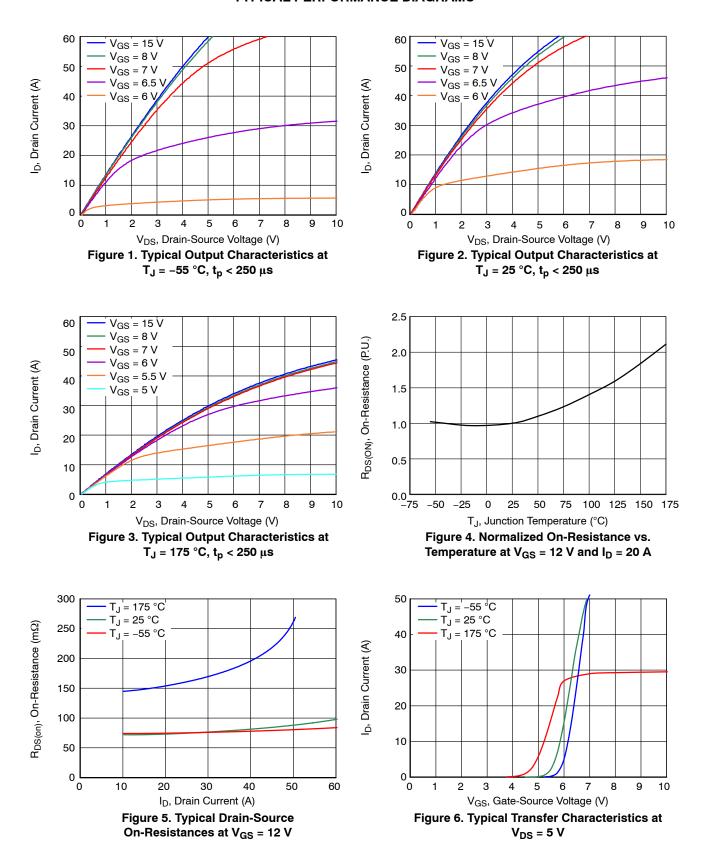
## **ELECTRICAL CHARACTERISTICS** ( $T_J = +25$ °C unless otherwise specified) (continued)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
TYPICAL PERFORMANCE - DYNAMIC	•				-	•
Turn-on Delay Time	t <sub>d(on)</sub>	$V_{DS} = 800 \text{ V}, I_{D} = 15 \text{ A},$	-	22	_	ns
Rise Time	t <sub>r</sub>	Gate Driver = $-5$ V to $+15$ V, R <sub>G ON</sub> = 1 $\Omega$ ,	-	16	_	
Turn-off Delay Time	t <sub>d(off)</sub>	$R_{GOFF}^- = 20 \Omega$ , Inductive Load.	-	67	-	
Fall Time	t <sub>f</sub>	FWD: Same Device with	-	12	-	
Turn-on Energy	E <sub>ON</sub>	$V_{GS} = 0 \text{ V and R}_{G} = 20 \Omega,$ $T_{J} = 150 ^{\circ}\text{C (Notes 5, 7)}$	-	381	-	μJ
Turn-off Energy	E <sub>OFF</sub>		-	41	-	
Total Switching Energy	E <sub>TOTAL</sub>		-	422	-	
Turn-on Delay Time	t <sub>d(on)</sub>	$\begin{split} &V_{DS} = 800 \text{ V, } I_D = 15 \text{ A,} \\ &\text{Gate Driver} = -5 \text{ V to } +15 \text{ V,} \\ &R_{G,ON} = 1  \Omega, \\ &R_{G,OF} = 1  \Omega, \\ &\text{Inductive Load,} \\ &\text{FWD: Same Device with} \\ &V_{GS} = 0 \text{ V and } R_G = 1  \Omega, \\ &\text{Snubber: } R_S = 5  \Omega \text{ and } C_S = 68 \text{ pF,} \\ &T_J = 25  ^{\circ}\text{C (Notes 6, 8)} \end{split}$	-	44	-	ns
Rise Time	t <sub>r</sub>		-	20	-	1 !
Turn-off Delay Time	t <sub>d(off)</sub>		-	32	-	
Fall Time	t <sub>f</sub>		-	17.6	-	
Turn-on Energy Including R <sub>S</sub> Energy	E <sub>ON</sub>		-	474	=	μJ
Turn-off Energy Including R <sub>S</sub> Energy	E <sub>OFF</sub>		-	62	-	
Total Switching Energy	E <sub>TOTAL</sub>		-	536	-	
Snubber R <sub>S</sub> Energy During Turn-on	E <sub>RS_ON</sub>		-	1	-	
Snubber R <sub>S</sub> Energy During Turn-off	E <sub>RS_OFF</sub>		-	0.7	_	
Turn-on Delay Time	t <sub>d(on)</sub>	$V_{DS} = 800 \text{ V}, I_{D} = 15 \text{ A},$	-	42.4	-	ns
Rise Time	t <sub>r</sub>	Gate Driver = $-5$ V to +15 V, R <sub>G ON</sub> = 1 $\Omega$ ,	-	19.2	-	
Turn-off Delay Time	t <sub>d(off)</sub>	RG OFF = 1 $\Omega$ , Inductive Load, FWD: Same Device with V <sub>GS</sub> = 0 V and R <sub>G</sub> = 1 $\Omega$ , Snubber: R <sub>S</sub> = 5 $\Omega$ and C <sub>S</sub> = 68 pF, T <sub>J</sub> = 150 °C (Notes 6, 8)	-	32.8	-	
Fall Time	t <sub>f</sub>		-	18.4	_	
Turn-on Energy Including R <sub>S</sub> Energy	E <sub>ON</sub>		-	450	_	μJ
Turn-off Energy Including R <sub>S</sub> Energy	E <sub>OFF</sub>		-	64	-	
Total Switching Energy	E <sub>TOTAL</sub>		-	514	-	
Snubber R <sub>S</sub> Energy During Turn-on	E <sub>RS_ON</sub>		-	0.9	-	
Snubber R <sub>S</sub> Energy During Turn-off	E <sub>RS_OFF</sub>	1	-	0.9	_	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product

- Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
  Limited by T<sub>J, max</sub>.
  Pulse width t<sub>p</sub> limited by T<sub>J, max</sub>.
  Measured with the half-bridge mode switching test circuit in Figure 23.
  Measured with the half-bridge mode switching test circuit in Figure 24.
  A bus RC snubber (R<sub>BS</sub> = 2.5 Ω, C<sub>BS</sub>=200 nF) must be applied to reduce the power loop high frequency oscillations.
  In this table, the switching energies (turn-on energy, turn-off energy and total energy) presented include the device RC snubber energy losses. losses.

#### **TYPICAL PERFORMANCE DIAGRAMS**



#### TYPICAL PERFORMANCE DIAGRAMS (continued)

V<sub>GS</sub>, Gate-Source Voltage (V)

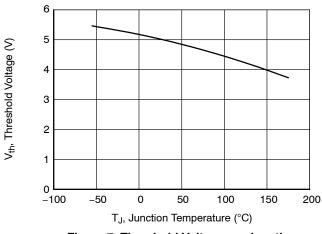


Figure 7. Threshold Voltage vs. Junction Temperature at  $V_{DS}$  = 5 V and  $I_{D}$  = 10 mA

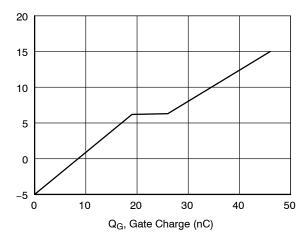


Figure 8. Typical Gate Charge at  $V_{DS} = 800 \text{ V}$  and  $I_{D} = 15 \text{ A}$ 

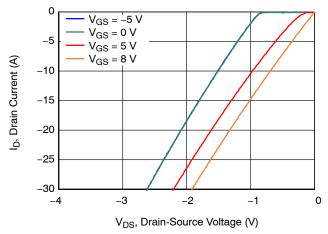


Figure 9.  $3^{rd}$  Quadrant Characteristics at  $T_J = -55$  °C

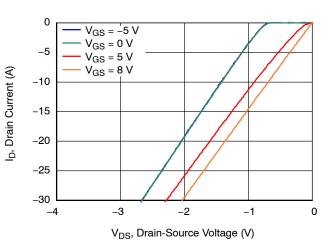


Figure 10.  $3^{rd}$  Quadrant Characteristics at  $T_J = 25$  °C

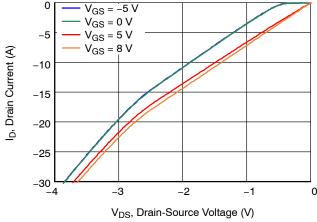


Figure 11.  $3^{rd}$  Quadrant Characteristics at  $T_J = 175$  °C

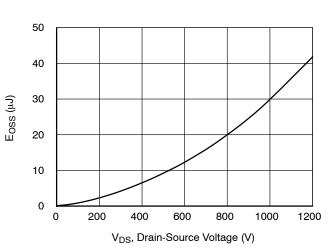


Figure 12. Typical Stored Energy in  $C_{OSS}$  at  $V_{GS} = 0 \text{ V}$ 

#### TYPICAL PERFORMANCE DIAGRAMS (continued)

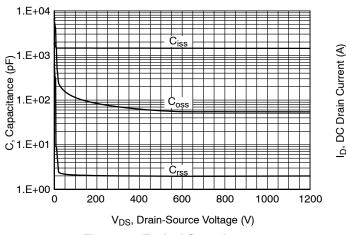


Figure 13. Typical Capacitances at f = 100 kHz and  $V_{GS} = 0 \text{ V}$ 

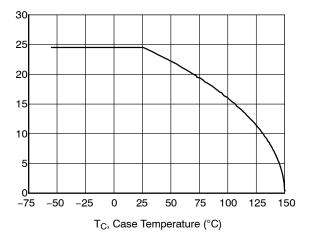


Figure 14. DC Drain Current Derating

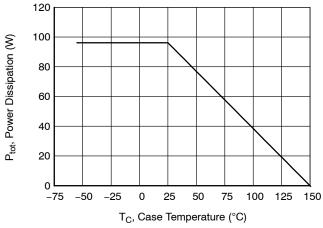


Figure 15. Total Power Dissipation

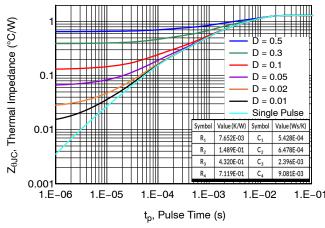


Figure 16. Maximum Transient Thermal Impedance and Parameters for Thermal Equivalent Circuit (Foster) Model

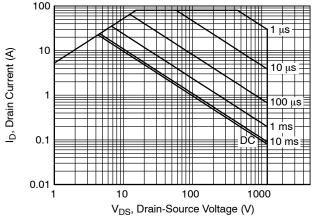


Figure 17. Safe Operation Area at  $T_C = 25$  °C, D = 0, Parameter  $t_p$ 

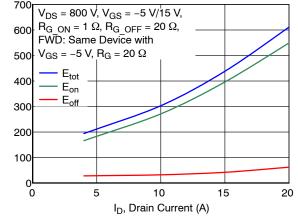


Figure 18. Clamped Inductive Switching Energy vs. Drain Current at  $T_J = 25$  °C

Switching Energy (µJ)

## TYPICAL PERFORMANCE DIAGRAMS (continued)

EOFF, Turn-off Energy Loss (μJ)

Q<sub>rr</sub> (nc)

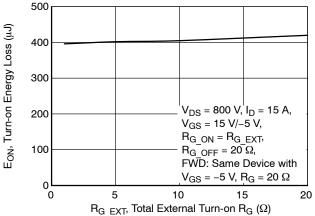


Figure 19. Clamped Inductive Switching Turn-On Energy vs. Turn-on Gate Resistance R<sub>G</sub>

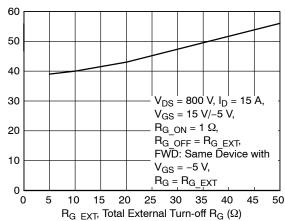


Figure 20. Clamped Inductive Switching Turn-Off Energy vs. Turn-off Gate Resistance R<sub>G</sub>

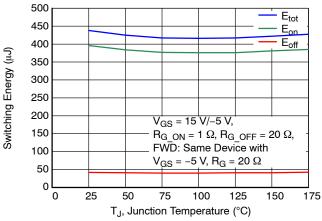


Figure 21. Clamped Inductive Switching Energy vs. Junction Temperature at  $V_{DS}$  = 800 V and  $I_{D}$  = 15 A

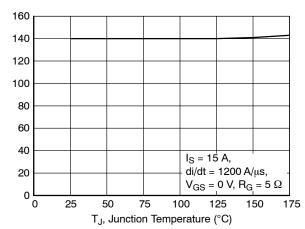


Figure 22. Reverse Recovery Charge  $Q_{rr}$  vs. Junction Temperature at  $V_{DS}$  = 800 V

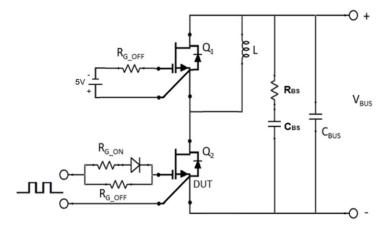


Figure 23. Schematic of the Half-Bridge Mode Switching Test Circuit. Note, a Bus RC Snubber (R<sub>BS</sub> = 2.5  $\Omega$ , C<sub>BS</sub> = 200 nF) is Used to Reduce the Power Loop High Frequency Oscillations

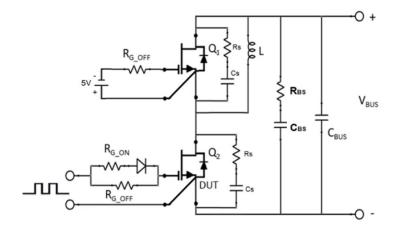


Figure 24. Schematic of the Half–Bridge Mode Switching Test Circuit with Device Snubbers (R<sub>S</sub> = 5  $\Omega$ , C<sub>S</sub> = 68 nF) and a RC Snubber (R<sub>BS</sub> = 2.5  $\Omega$ , C<sub>BS</sub> = 200 nF)

#### **APPLICATIONS INFORMATION**

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ( $R_{DS(on)}$ ), output capacitance ( $C_{oss}$ ), gate charge ( $Q_G$ ), and reverse recovery charge ( $Q_{rr}$ ) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is

working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see <a href="https://www.onsemi.com">www.onsemi.com</a>.

A snubber circuit with a small  $R_{(G)}$ , or gate resistor, provides better EMI suppression with higher efficiency compared to using a high  $R_{(G)}$  value. There is no extra gate delay time when using the snubber circuitry, and a small  $R_{(G)}$  will better control both the turn-off  $V_{(DS)}$  peak spike and ringing duration, while a high  $R_{(G)}$  will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high  $R_{(G)}$ , while greatly reducing  $E_{(OFF)}$  from mid-to-full load range with only a small increase in  $E_{(ON)}$ . Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the **onsemi** website at www.onsemi.com.

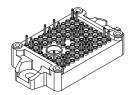
#### **ORDERING INFORMATION**

Part Number	Marking	Package	Shipping
UFB15C12E1BC3N	UFB15C12E1BC3N	PIM20 (Pb-Free)	24 Units / Tray

#### **REVISION HISTORY**

Revision	Description of Changes	Date
D	Acquired the original Qorvo JFET Division Data Sheet and updated the main document title to comply with <b>onsemi</b> standards for SiC products.	1/15/2025
5	Converted the Data Sheet to <b>onsemi</b> format.	06/04/2025





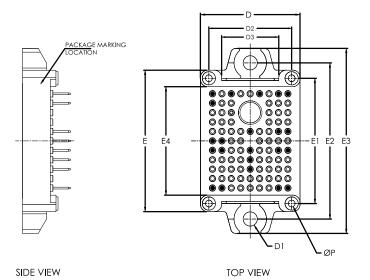
# PIM20 33.80x42.50x12.00 E1B FULL BRIDGE (SOLDER PIN)

CASE 180DG ISSUE O

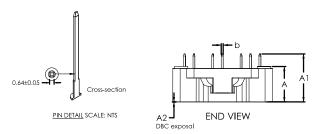
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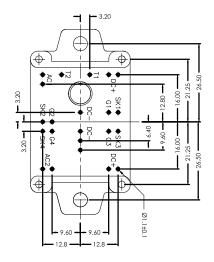
#### NOTES:

1.CONTROLLING DIMENSION: MILLIMETERS
2. PIN POSITION TOLERANCIS ±0.40mm



	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	11.65	12.00	12.35			
A1	15.75	16.25	16.75			
A2	0.15	0.50	0.85			
b	0.59	0.64	0.69			
D	33.50	33.80	34.10			
D1	Ø4.7	Ø4.8	Ø <b>4.9</b>			
D2	27.90	28.10	28.30			
D3	19.20	19.40	19.60			
E	47.70	48.00	48.30			
E1	42.30	42.50	42.70			
E2	52.90	53.00	53.10			
E3	62.30	62.80	63.30			
E4	36.60	36.80	37.00			
Р	Ø2.2	Ø2.3	Ø2.4			





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